

**8 bit 30/50 MSPS Flash A/D Converter**

Evaluation Board Available — CXA1016PPCB/CXA1016KPCB  
CXA1056PPCB/CXA1056KPCB

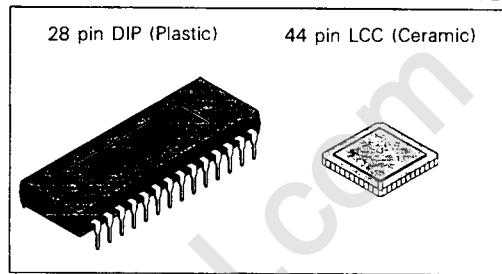
**Description**

CXA1016P/CXA1016K/CXA1056P/CXA1056K are 8 bit high-speed A/D converter ICs for various applications. They can be used widely for various purposes which require high-speed A/D conversions.

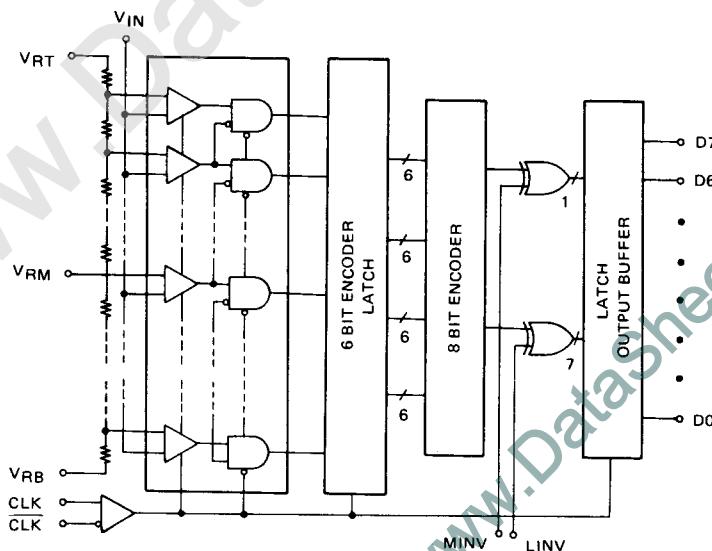
CXA1016P/CXA1056P are assembled in the plastic DIP packages and CXA1016K/CXA1056K are in the ceramic lead-less chip carriers.

**Features (CXA1016P/CXA1016K)**

- Resolution 8 bits  $\pm$  1/2 LSB
- High-speed operation Maximum conversion Rate 30 MSPS
- Wide analog input bandwidth 30MHz (-3dB)
- Low input capacitance 35 pF (typ)
- Low power consumption 420 mW (typ)

**Features (CXA1056P/CXA1056K)**

- Resolution 8 bits  $\pm$  1/2 LSB
- High-speed operation Maximum conversion Rate 50 MSPS
- Wide analog input bandwidth 50MHz (-3dB)
- Low input capacitance 35 pF (typ)
- Low power consumption 550 mW (typ)

**Block Diagram**

**Absolute Maximum Ratings (Ta=25°C)**

• Supply voltage	V <sub>EE</sub>	0 to -7	V
• Analog input voltage	V <sub>IN</sub>	0.5 to V <sub>EE</sub>	V
• Reference input voltage	V <sub>RT</sub> , V <sub>RB</sub> , V <sub>RM</sub>	0.5 to V <sub>EE</sub>	V
	V <sub>RT</sub> -V <sub>RB</sub>	2.5	V
• Digital input voltage	CLK, CLK, MINV, LINV	0.5 to -4	V
• VRM pin input current	I <sub>VRM</sub>	-3 to +3	mA
• Digital output current	I <sub>D0</sub> to I <sub>D7</sub>	0 to -10	mA
• Operating temperature	T <sub>a</sub>	-20 to +100	°C (CXA1016P/CXA1056P)
	T <sub>c</sub>	-25 to +125	°C (CXA1016K/CXA1056K) <sup>*1</sup>
• Storage temperature	T <sub>stg</sub>	-55 to +150	°C
• Allowable power dissipation	P <sub>d</sub>	1.48	W (CXA1016P/CXA1056P)
		1.08	W (CXA1016K/CXA1056K)

\*1 Heat sinking is required above 100°C (CXA1016K)/86°C (CXA1056K).

**Recommended Operating Conditions (CXA1016P/CXA1016K)**

		Min.	Typ.	Max.	Unit
• Supply voltage	A <sub>VEE</sub> , D <sub>VEE</sub>	-5.7	-5.2	-5.0	V
	A <sub>VEE</sub> -D <sub>VEE</sub>	-0.05	0	0.05	V
	AGND-DGND	-0.05	0	0.05	V
• Reference input voltage	V <sub>RT</sub>	-0.1	0	0.1	V
	V <sub>RB</sub>	-2.2	-2	-1.8	V
• Analog input voltage	V <sub>IN</sub>	V <sub>RB</sub> V <sub>RT</sub>			
• Clock pulse width	T <sub>pw1</sub>	25			ns
	T <sub>pw0</sub>	8			ns

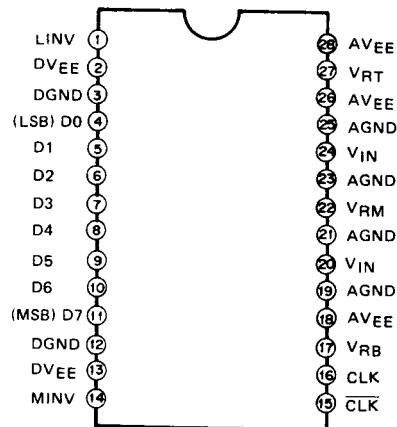
**Recommended Operating Conditions (CXA1056P/CXA1056K)**

		Min.	Typ.	Max.	Unit
• Supply voltage	A <sub>VEE</sub> , D <sub>VEE</sub>	-5.7	-5.2	-5.0	V
	A <sub>VEE</sub> -D <sub>VEE</sub>	-0.05	0	0.05	V
	AGND-DGND	-0.05	0	0.05	V
• Reference input voltage	V <sub>RT</sub>	-0.1	0	0.1	V
	V <sub>RB</sub>	-2.2	-2	-1.8	V
• Analog input voltage	V <sub>IN</sub>	V <sub>RB</sub> V <sub>RT</sub>			
• Clock pulse width	T <sub>pw1</sub>	15			ns
	T <sub>pw0</sub>	5			ns

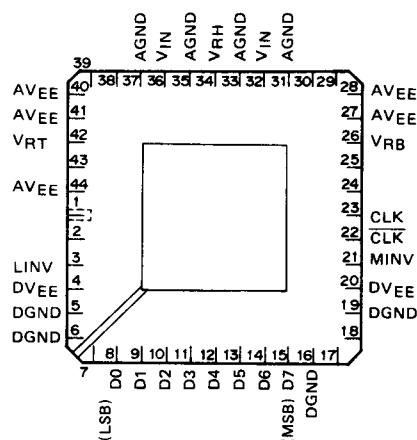
### **Pin Configuration (Top View)**

The pin numbers without indication are empty pins. (not connected)

CXA1016P/CXA1056P



CXA1016K/CXA1056K



**Pin Description**

Symbol	Function
AVEE	Analog VEE, -5.2V (typ). Coupled with $\sim 6\Omega$ between DVEE.
LINV	Input pin for output polarity inversion of Do (LSB)~D6. (See the code table)
DVEE	Digital VEE, -5.2V (typ).
DGND	Digital GND, which is separated from the Analog GND.
D <sub>0</sub> ~D <sub>7</sub>	Digital data output pin, ECL level. Do: LSB~D <sub>7</sub> : MSB. Pull-down resistors are necessary externally.
MINV	Input pin for output polarity inversion of D <sub>7</sub> (MSB) (See the code table). ECL level. "0" level is held when it is released.
CLK	Inverse clock input pin, ECL level.
CLK	Clock input pin, ECL level.
V <sub>RB</sub>	Reference voltage (bottom), -2V (typ).
AGND	Analog GND
V <sub>IN</sub>	Analog input, input range is V <sub>RT</sub> ~V <sub>RB</sub>
V <sub>RM</sub>	Middle point of the reference voltage, it can be used as a linearity correction pin.
V <sub>RT</sub>	Reference voltage (top), OV (typ).
	Empty pins (not connected), 2 and 19 are used to be grounded to DGND, the others are used to be grounded to AGND.

**Output Coding**

MINV LINV	0 0	0 1	1 0	1 1
OV	111...11	100...00	011...11	000...00
.	111...10	100...01	011...10	000...01
.	.	.	.	.
.	.	.	.	.
V <sub>IN</sub>	100...00	111...11	000...00	011...11
.	011...11	000...00	111...11	100...00
.	.	.	.	.
.	.	.	.	.
-2V	000...01	011...10	100...01	111...10
	000...00	011...11	100...00	111...11

1: V<sub>IH</sub>, V<sub>OH</sub>0: V<sub>IL</sub>, V<sub>OL</sub>

**Electrical Characteristics (CXA1016P/CXA1016K)**

(Ta=25°C, VEE=-5.2V, VRT=0V, VRB=-2V)

Item	Symbol	Condition	Min.	Typ.	Max.	Unit
Maximum Conversion Rate	F <sub>c</sub>	V <sub>IN</sub> =0 to -2V, fin=1 kHz, ramp	30			MSPS
Supply Current	I <sub>EE</sub>			-75	-100	mA
Analog Input Capacitance	C <sub>IN</sub>	V <sub>IN</sub> =-1V+0.07 Vrms		35	40	pF
Analog Input Bias Current	I <sub>IN</sub>	V <sub>IN</sub> =-1V		60	90	μA
Reference Resistor	R <sub>r</sub> (VRT~VRB)		70	80	100	Ω
Offset Voltage	V <sub>RT</sub>		7	9	11	mV
	V <sub>RB</sub>		15	17	19	mV
Digital Input Voltage	V <sub>IH</sub>		-1.0	-0.9	-0.7	V
	V <sub>IL</sub>		-1.9	-1.75	-1.6	V
Digital Input Current	I <sub>IH</sub>	V <sub>IH</sub> =-0.9V	0		0.4	mA
	I <sub>IL</sub>	V <sub>IL</sub> =-1.75V	-0.05		0.35	mA
Digital Output Voltage	V <sub>OH</sub>	R <sub>l</sub> =620Ω ~ V <sub>EE</sub>	-1.0			V
	V <sub>OL</sub>				-1.6	V
Output Data Delay	T <sub>d</sub>	R <sub>l</sub> =620Ω ~ V <sub>EE</sub>		4.0	5.0	ns
Non-linearity Error		F <sub>c</sub> = 30 MSPS, V <sub>IN</sub> =0 to -2V, fin=1 kHz, ramp			±1/2	LSB
Differential Non-linearity Error		F <sub>c</sub> = 30 MSPS			±1/2	LSB
Differential Gain	DG	NTSC 40 IRE mod. ramp, F <sub>c</sub> = 30 MSPS			1.5.	%
Differential Phase	DP				0.5	deg.
Aperture Jitter	T <sub>AJ</sub>			45		ps
Sampling Delay	T <sub>SD</sub>		6.3	6.8	7.3	ns
Full scale input BW (-3dB)	BW <sub>F</sub>	*1		30		MHz

\*1 Source impedance = 50 Ω

Without a buffer amplifier driving A/D input

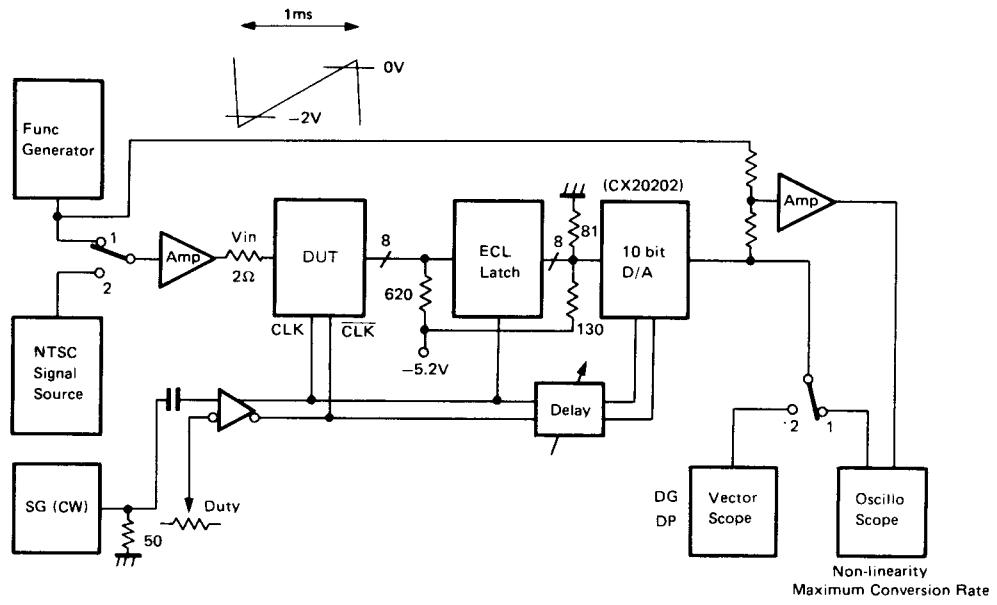
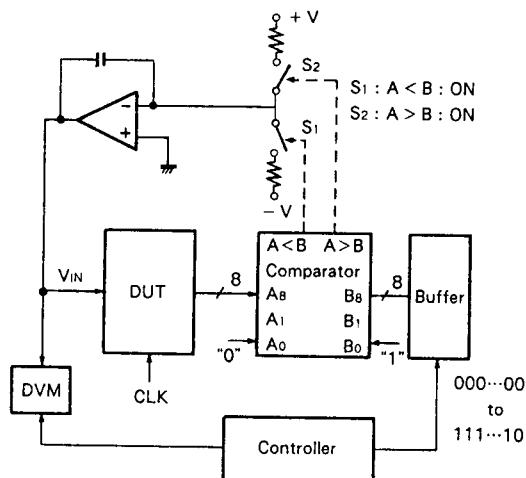
## Electrical Characteristics (CXA1056P/CXA1056K)

(Ta=25°C, VEE=-5.2V, VRT=0V, VRB=-2V)

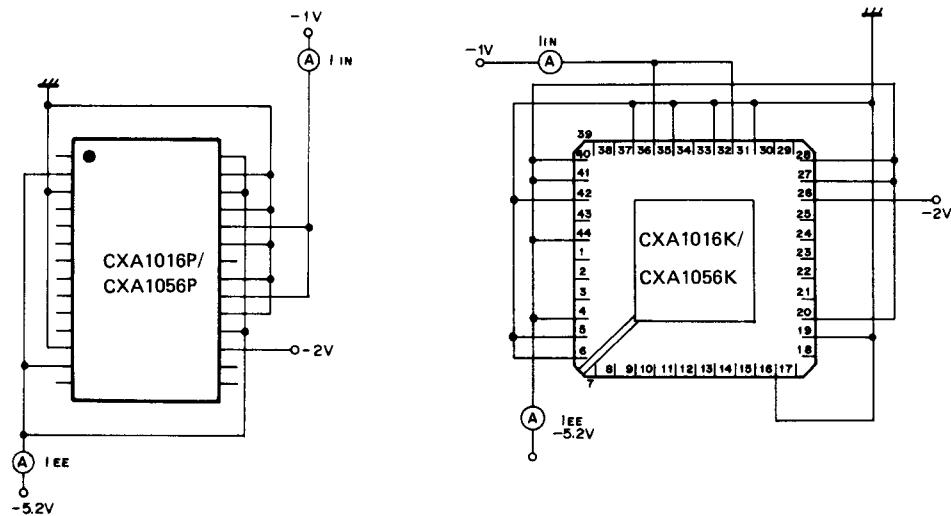
Item	Symbol	Condition	Min.	Typ.	Max.	Unit
Maximum Conversion Rate	F <sub>c</sub>	V <sub>IN</sub> =0 to -2V, f <sub>in</sub> =1 kHz, ramp	50			MSPS
Supply Current	I <sub>EE</sub>			-95	-120	mA
Analog Input Capacitance	C <sub>IN</sub>	V <sub>IN</sub> =-1V+0.07 Vrms		35	40	pF
Analog Input Bias Current	I <sub>IN</sub>	V <sub>IN</sub> =-1V		75	115	μA
Reference Resistor	R <sub>r</sub> (VRT~VRB)		70	80	100	Ω
Offset Voltage	V <sub>RT</sub>		7	9	11	mV
	V <sub>RB</sub>		15	17	19	mV
Digital Input Voltage	V <sub>IH</sub>		-1.0	-0.9	-0.7	V
	V <sub>IL</sub>		-1.9	-1.75	-1.6	V
Digital Input Current	I <sub>IH</sub>	V <sub>IH</sub> =-0.9V	0		0.4	mA
	I <sub>IL</sub>	V <sub>IL</sub> =-1.75V	-0.05		0.35	mA
Digital Output Voltage	V <sub>OH</sub>	R <sub>l</sub> =620Ω ~ V <sub>EE</sub>	-1.0			V
	V <sub>OL</sub>				-1.6	V
Output Data Delay	T <sub>d</sub>	R <sub>l</sub> =620Ω ~ V <sub>EE</sub>		4.0	5.0	ns
Non-linearity Error		F <sub>c</sub> = 50 MSPS, V <sub>IN</sub> =0 to -2V, f <sub>in</sub> =1 kHz, ramp			±1/2	LSB
Differential Non-linearity Error		F <sub>c</sub> = 50 MSPS			±1/2	LSB
Differential Gain	DG	NTSC 40 IRE mod. ramp, F <sub>c</sub> = 50 MSPS			1.5	%
Differential Phase	DP				0.5	deg.
Aperture Jitter	T <sub>aj</sub>			30		ps
Sampling Delay	T <sub>sd</sub>		5.4	5.7	6.0	ns
Full scale input BW (-3dB)	BW <sub>F</sub>	*1		50		MHz

\*1 Source impedance = 50 Ω

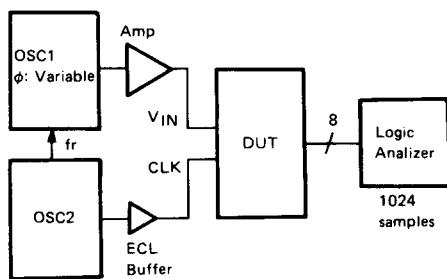
Without a buffer amplifier driving A/D input

**Electrical Characteristics Test Circuit****Maximum Conversion Frequency Test Circuit****Differential Gain Error Test Circuit****Differential Phase Error Test Circuit****Differential Non-linearity Test Circuit****Integral Non-linearity Test Circuit**

**Power Supply Current Test Circuit**  
**Analog Input Bias Current Test Circuit**

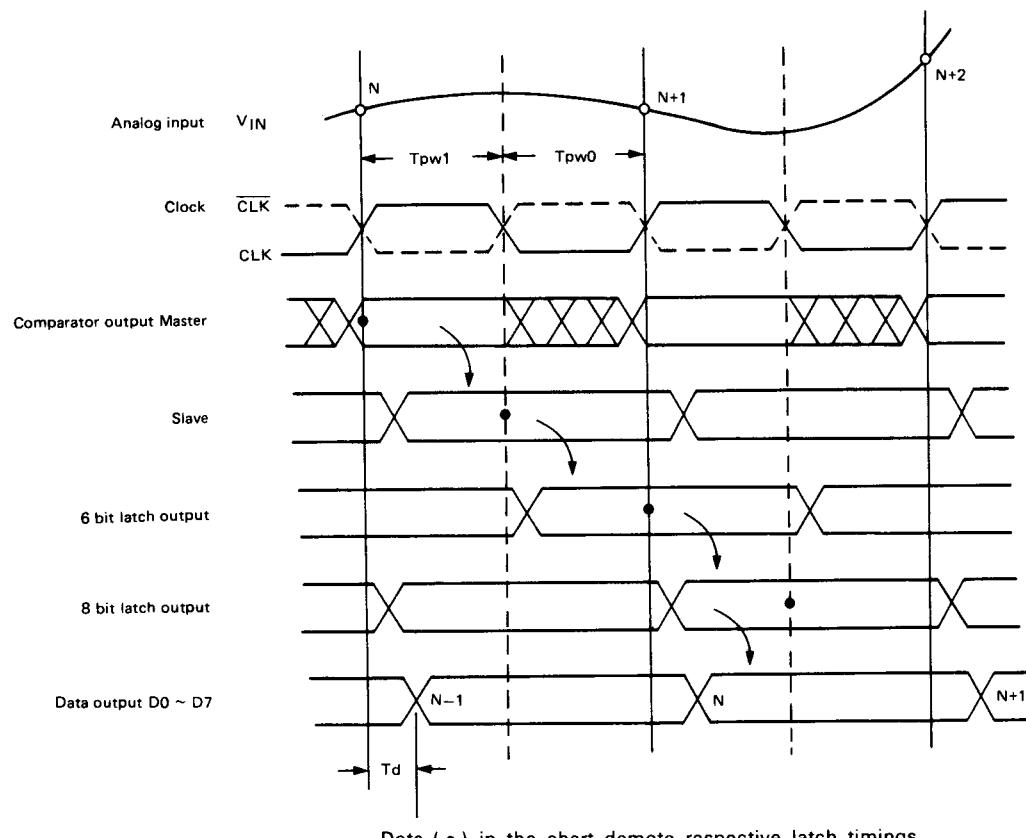


**Aperture Jitter Test Circuit**



**Description of Function** (See the block diagram and timing chart.)

1. The reference voltage, which is obtained by dividing equally the voltage across V<sub>RT</sub> to V<sub>RB</sub> into 256 by the reference resistor ladder, is applied to the respective  $\oplus$  (positive) input sides of 256 clocked comparators. An analog input is applied to the  $\ominus$  (negative) input sides of all the 256 clocked comparators from the V<sub>IN</sub> pin.
2. When the state of CLK is in Low, the master (front stage) of the comparator compares the respective reference voltage and the analog input voltage which is ever-changing.
3. When the CLK moves from Low into Hi, each master latches the state immediately prior to the above simultaneously, and as a result, it provides conditions of "11 . . . 1100 . . 0" in sequence from the V<sub>RT</sub> side to the V<sub>RB</sub> side.
4. The output of the master is ANDed between the respective adjacent outputs, and "1" stands only when neighboring 2 outputs become "10", and the all other outputs become "0".
5. The result of the AND is latched when CLK moves from Hi into Low. Output of the slave is divided into 4 blocks and each block has 32 clocked comparators, and they are coded into binary codes of 6 bits respectively by the transistor matrix circuit.
6. The 6 bit codes are further coded into 8 bit codes by the transistor matrix circuit after they are respectively latched, and they are then output into the ECL level by the output buffer after being 8 bit latched. The output data is delayed 1 clock from the data sampling point and appears at the output pin.
7. Two polarity inversion inputs such as MINV and LINV are fed externally to the output buffer, and each of them selects output polarity of MSB and other polarity than MSB respectively.

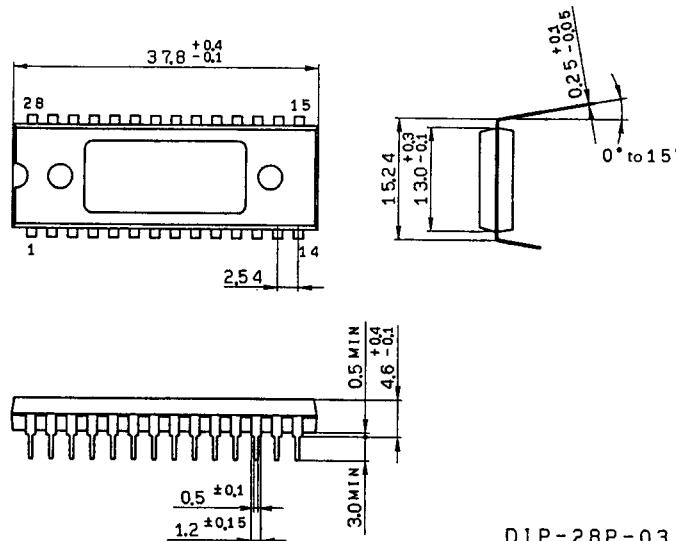
**Timing Chart**

Dots (•) in the chart denote respective latch timings.

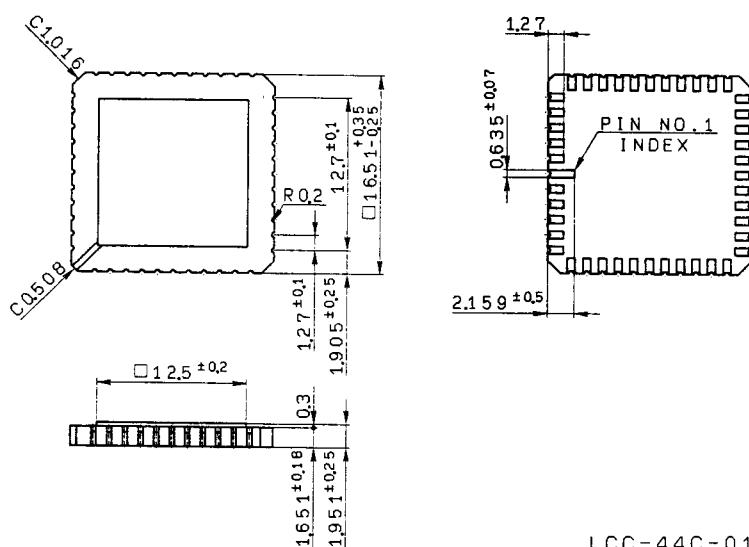
\*See page 54 for  $T_{pw1}$  and  $T_{pw0}$ .

## Package Outline      Unit: mm

CXA1016P/CXA1056P    28 pin DIP (Plastic)

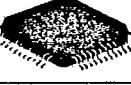


CXA1016K/CXA1056K    44 pin LCC (Ceramic)



T-90-20

## Sony Package Product Name

Type	Package name		Package	Features				
	Symbol	Description		Material*	Lead pitch	Lead shape	Lead pull out direction	
Inserted	D I P	DUAL IN LINE PACKAGE		P C	2.54mm (100MIL)	Through Hole Lead	2-direction	
	S I P	SINGLE IN LINE PACKAGE		P	2.54mm (100MIL)	Through Hole Lead	1-direction	
	Z I P	ZIG ZAG IN LINE PACKAGE		P	2.54mm (100MIL) Zig Zag inline	Through Hole Lead	1-direction	
	P G A	PIN GRID ARRAY		C	2.54mm (100MIL)	Through Hole Lead	4-direction	
	PIGGY BACK	PIGGY BACK		C	2.54mm (100MIL)	Through Hole Lead	2-direction	
	Shrink	SDIP	SHRINK DUAL IN LINE PACKAGE		P	1.778mm (70MIL)	Through Hole Lead	2-direction
Surface mounted	Standard flat package	Q F P	QUAD FLAT PACKAGE		P	1.0mm 0.8mm	Gull- Wing	4-direction
		S O P	SMALL- OUTLINE PACKAGE		P	1.27mm (50MIL)	Gull- Wing	2-direction
	Shrink flat package	V Q F P	VERY SMALL QUAD FLAT PACKAGE		P	0.5mm	Gull- Wing	4-direction
		V S O P	VERY SMALL OUTLINE PACKAGE		P	0.65mm	Gull Wing	2-direction
	Standard chip carrier	P L C C	PLASTIC LEADED CHIP CARRIER		P	1.27mm (50MIL)	J-bend	4-direction
		L C C	LEAD LESS CHIP CARRIER		C	1.27mm (50MIL)	Lead less	Package side
	Shrink chip carrier	S P L C C (P L C C)	SHRINK PLASTIC LEADED CHIP CARRIER		P	1.27mm Max. (50MIL Max.)	J-bend	4-direction
	Standard 2-direction chip carrier	S O J	SMALL OUTLINE J-LEAD PACKAGE		P	1.27mm (50MIL)	J-bend	2-direction

\* P.....Plastic, C.....Ceramic